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Understanding [Embedded - FPGAs \(Field Programmable Gate Array\)](#)

Embedded - FPGAs, or Field Programmable Gate Arrays, are advanced integrated circuits that offer unparalleled flexibility and performance for digital systems. Unlike traditional fixed-function logic devices, FPGAs can be programmed and reprogrammed to execute a wide array of logical operations, enabling customized functionality tailored to specific applications. This reprogrammability allows developers to iterate designs quickly and implement complex functions without the need for custom hardware.

Applications of Embedded - FPGAs

The versatility of Embedded - FPGAs makes them indispensable in numerous fields. In telecommunications.

Details

Product Status	Obsolete
Number of LABs/CLBs	1452
Number of Logic Elements/Cells	-
Total RAM Bits	-
Number of I/O	81
Number of Gates	24000
Voltage - Supply	2.25V ~ 5.25V
Mounting Type	Surface Mount
Operating Temperature	-40°C ~ 85°C (TA)
Package / Case	100-LQFP
Supplier Device Package	100-TQFP (14x14)
Purchase URL	https://www.e-xfl.com/product-detail/microchip-technology/a54sx16a-2tq100i

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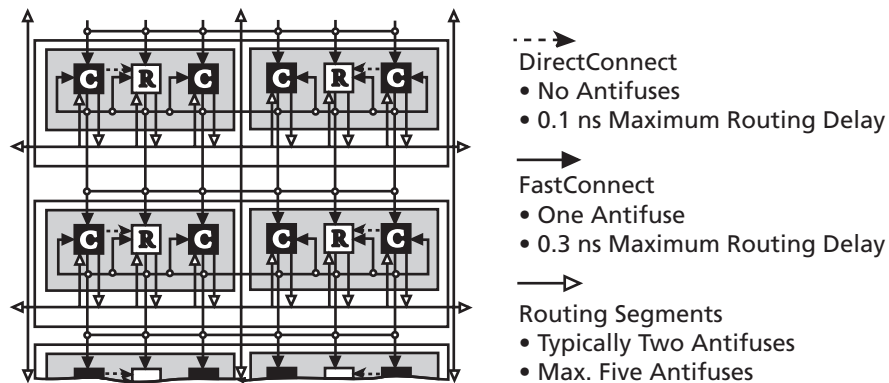


Figure 1-5 • DirectConnect and FastConnect for Type 1 SuperClusters

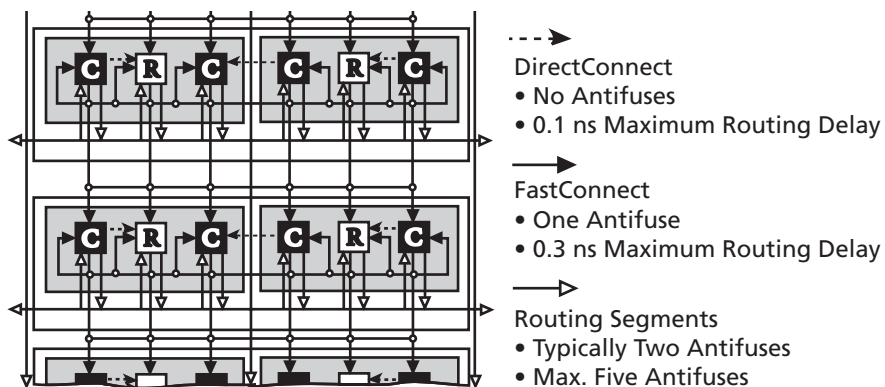


Figure 1-6 • DirectConnect and FastConnect for Type 2 SuperClusters

Other Architectural Features

Technology

The Actel SX-A family is implemented on a high-voltage, twin-well CMOS process using $0.22\ \mu\text{m} / 0.25\ \mu\text{m}$ design rules. The metal-to-metal antifuse is comprised of a combination of amorphous silicon and dielectric material with barrier metals and has a programmed ('on' state) resistance of $25\ \Omega$ with capacitance of $1.0\ \text{fF}$ for low signal impedance.

Performance

The unique architectural features of the SX-A family enable the devices to operate with internal clock frequencies of 350 MHz, causing very fast execution of even complex logic functions. The SX-A family is an optimal platform upon which to integrate the functionality previously contained in multiple complex programmable logic devices (CPLDs). In addition, designs that previously would have required a gate array to meet performance goals can be integrated into an SX-A device with dramatic improvements in cost and time-to-market. Using timing-driven place-and-route tools, designers can achieve highly deterministic device performance.

User Security

Reverse engineering is virtually impossible in SX-A devices because it is extremely difficult to distinguish between programmed and unprogrammed antifuses. In addition, since SX-A is a nonvolatile, single-chip solution, there is no configuration bitstream to intercept at device power-up.

The Actel FuseLock advantage ensures that unauthorized users will not be able to read back the contents of an Actel antifuse FPGA. In addition to the inherent strengths of the architecture, special security fuses that prevent internal probing and overwriting are hidden throughout the fabric of the device. They are located where they cannot be accessed or bypassed without destroying access to the rest of the device, making both invasive and more-subtle noninvasive attacks ineffective against Actel antifuse FPGAs.

Look for this symbol to ensure your valuable IP is secure (Figure 1-11).



Figure 1-11 • FuseLock

For more information, refer to Actel's [Implementation of Security in Actel Antifuse FPGAs](#) application note.

I/O Modules

For a simplified I/O schematic, refer to Figure 1 in the application note, [Actel eX, SX-A, and RTSX-S I/Os](#).

Each user I/O on an SX-A device can be configured as an input, an output, a tristate output, or a bidirectional pin. Mixed I/O standards can be set for individual pins, though this is only allowed with the same voltage as the input. These I/Os, combined with array registers, can achieve clock-to-output-pad timing as fast as 3.8 ns, even without the dedicated I/O registers. In most FPGAs, I/O cells that have embedded latches and flip-flops, requiring instantiation in HDL code; this is a design complication not encountered in SX-A FPGAs. Fast pin-to-pin timing ensures that the device is able to interface with any other device in the system, which in turn enables parallel design of system components and reduces overall design time. All unused I/Os are configured as tristate outputs by the Actel Designer software, for maximum flexibility when designing new boards or migrating existing designs.

SX-A I/Os should be driven by high-speed push-pull devices with a low-resistance pull-up device when being configured as tristate output buffers. If the I/O is driven by a voltage level greater than V_{CC1} and a fast push-pull device is NOT used, the high-resistance pull-up of the driver and the internal circuitry of the SX-A I/O may create a voltage divider. This voltage divider could pull the input voltage below specification for some devices connected to the driver. A logic '1' may not be correctly presented in this case. For example, if an open drain driver is used with a pull-up resistor to 5 V to provide the logic '1' input, and V_{CC1} is set to 3.3 V on the SX-A device, the input signal may be pulled down by the SX-A input.

Each I/O module has an available power-up resistor of approximately $50\ \text{k}\Omega$ that can configure the I/O in a known state during power-up. For nominal pull-up and pull-down resistor values, refer to [Table 1-4 on page 1-8](#) of the application note [Actel eX, SX-A, and RTSX-S I/Os](#). Just slightly before V_{CCA} reaches 2.5 V, the resistors are disabled, so the I/Os will be controlled by user logic. See [Table 1-2 on page 1-8](#) and [Table 1-3 on page 1-8](#) for more information concerning available I/O features.

Boundary-Scan Testing (BST)

All SX-A devices are IEEE 1149.1 compliant and offer superior diagnostic and testing capabilities by providing Boundary Scan Testing (BST) and probing capabilities. The BST function is controlled through the special JTAG pins (TMS, TDI, TCK, TDO, and TRST). The functionality of the JTAG pins is defined by two available modes: Dedicated and Flexible. TMS cannot be employed as a user I/O in either mode.

Dedicated Mode

In Dedicated mode, all JTAG pins are reserved for BST; designers cannot use them as regular I/Os. An internal pull-up resistor is automatically enabled on both TMS and TDI pins, and the TMS pin will function as defined in the IEEE 1149.1 (JTAG) specification.

To select Dedicated mode, the user must reserve the JTAG pins in Actel's Designer software. Reserve the JTAG pins by checking the **Reserve JTAG** box in the Device Selection Wizard (Figure 1-12).

The default for the software is Flexible mode; all boxes are unchecked. Table 1-5 lists the definitions of the options in the Device Selection Wizard.



Figure 1-12 • Device Selection Wizard

Table 1-5 • Reserve Pin Definitions

Pin	Function
Reserve JTAG	Keeps pins from being used and changes the behavior of JTAG pins (no pull-up on TMS)
Reserve JTAG Test Reset	Regular I/O or JTAG reset with an internal pull-up
Reserve Probe	Keeps pins from being used or regular I/O

Flexible Mode

In Flexible mode, TDI, TCK, and TDO may be employed as either user I/Os or as JTAG input pins. The internal resistors on the TMS and TDI pins are not present in flexible JTAG mode.

To select the Flexible mode, uncheck the **Reserve JTAG** box in the Device Selection Wizard dialog in the Actel Designer software. In Flexible mode, TDI, TCK, and TDO pins may function as user I/Os or BST pins. The functionality is controlled by the BST Test Access Port (TAP) controller. The TAP controller receives two control inputs, TMS and TCK. Upon power-up, the TAP controller enters the Test-Logic-Reset state. In this state, TDI, TCK, and TDO function as user I/Os. The TDI, TCK, and TDO are transformed from user I/Os into BST pins when a rising edge on TCK is detected while TMS is at logic low. To return to Test-Logic Reset state, TMS must be high for at least five TCK cycles. **An external 10 k pull-up resistor to V_{CC} should be placed on the TMS pin to pull it High by default.**

Table 1-6 describes the different configuration requirements of BST pins and their functionality in different modes.

Table 1-6 • Boundary-Scan Pin Configurations and Functions

Mode	Designer "Reserve JTAG" Selection	TAP Controller State
Dedicated (JTAG)	Checked	Any
Flexible (User I/O)	Unchecked	Test-Logic-Reset
Flexible (JTAG)	Unchecked	Any EXCEPT Test-Logic-Reset

TRST Pin

The TRST pin functions as a dedicated Boundary-Scan Reset pin when the **Reserve JTAG Test Reset** option is selected as shown in Figure 1-12. An internal pull-up resistor is permanently enabled on the TRST pin in this mode. Actel recommends connecting this pin to ground in normal operation to keep the JTAG state controller in the Test-Logic-Reset state. When JTAG is being used, it can be left floating or can be driven high.

When the **Reserve JTAG Test Reset** option is not selected, this pin will function as a regular I/O. If unused as an I/O in the design, it will be configured as a tristated output.

PCI Compliance for the SX-A Family

The SX-A family supports 3.3 V and 5 V PCI and is compliant with the PCI Local Bus Specification Rev. 2.1.

Table 2-7 • DC Specifications (5 V PCI Operation)

Symbol	Parameter	Condition	Min.	Max.	Units
V _{CCA}	Supply Voltage for Array		2.25	2.75	V
V _{CCI}	Supply Voltage for I/Os		4.75	5.25	V
V _{IH}	Input High Voltage		2.0	5.75	V
V _{IL}	Input Low Voltage		–0.5	0.8	V
I _{IH}	Input High Leakage Current ¹	V _{IN} = 2.7	–	70	μA
I _{IL}	Input Low Leakage Current ¹	V _{IN} = 0.5	–	–70	μA
V _{OH}	Output High Voltage	I _{OUT} = –2 mA	2.4	–	V
V _{OL}	Output Low Voltage ²	I _{OUT} = 3 mA, 6 mA	–	0.55	V
C _{IN}	Input Pin Capacitance ³		–	10	pF
C _{CLK}	CLK Pin Capacitance		5	12	pF

Notes:

1. Input leakage currents include hi-Z output leakage for all bidirectional buffers with tristate outputs.
2. Signals without pull-up resistors must have 3 mA low output current. Signals requiring pull-up must have 6 mA; the latter includes FRAME#, IRDY#, TRDY#, DEVSEL#, STOP#, SERR#, PERR#, LOCK#, and, when used AD[63::32], C/BE[7::4]#, PAR64, REQ64#, and ACK64#.
3. Absolute maximum pin capacitance for a PCI input is 10 pF (except for CLK).

Figure 2-2 shows the 3.3 V PCI V/I curve and the minimum and maximum PCI drive characteristics of the SX-A family.

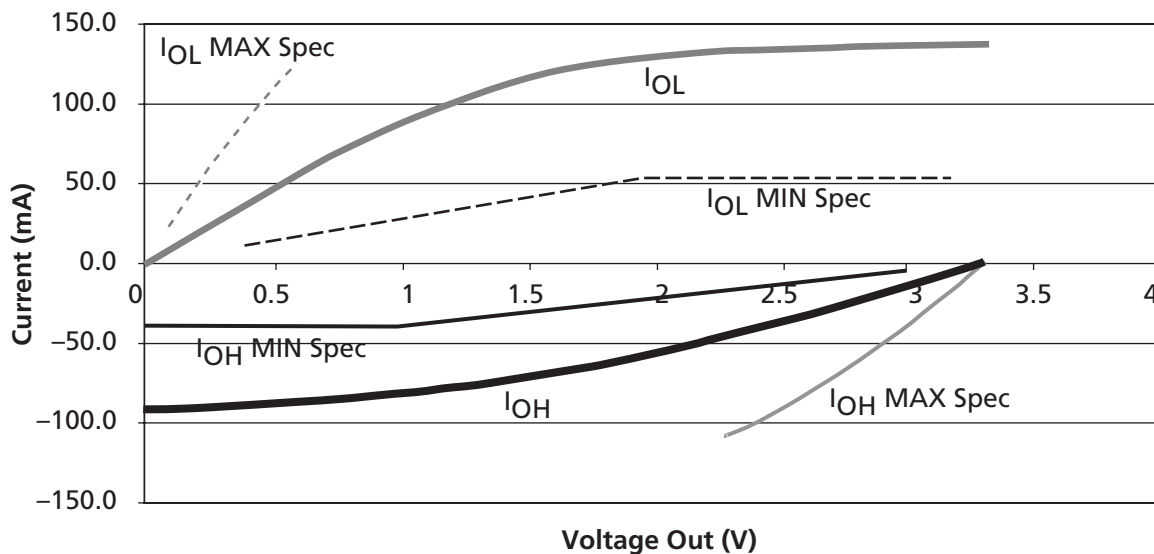


Figure 2-2 • 3.3 V PCI V/I Curve for SX-A Family

$$I_{OH} = (98.0/V_{CCI}) * (V_{OUT} - V_{CCI}) * (V_{OUT} + 0.4V_{CCI})$$

for $0.7 V_{CCI} < V_{OUT} < V_{CCI}$

EQ 2-3

$$I_{OL} = (256/V_{CCI}) * V_{OUT} * (V_{CCI} - V_{OUT})$$

for $0V < V_{OUT} < 0.18 V_{CCI}$

EQ 2-4

Output Buffer Delays

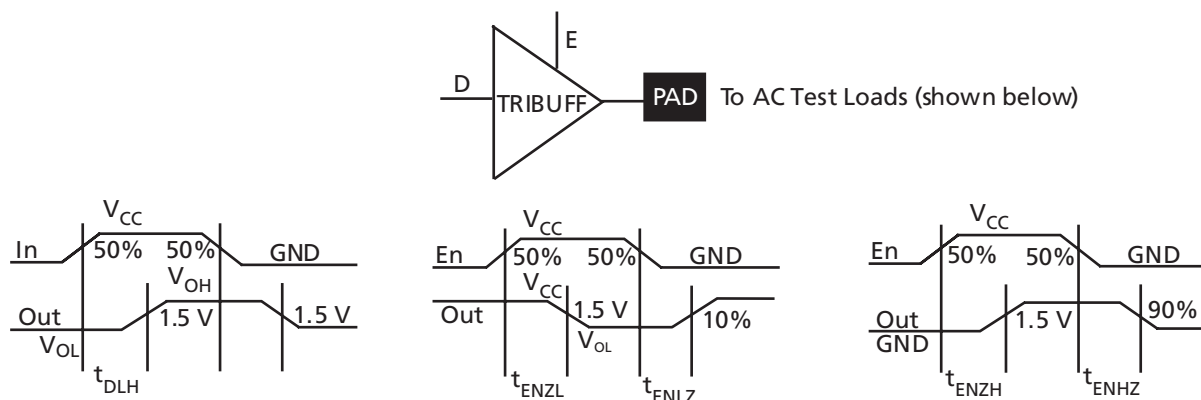


Figure 2-4 • Output Buffer Delays

AC Test Loads

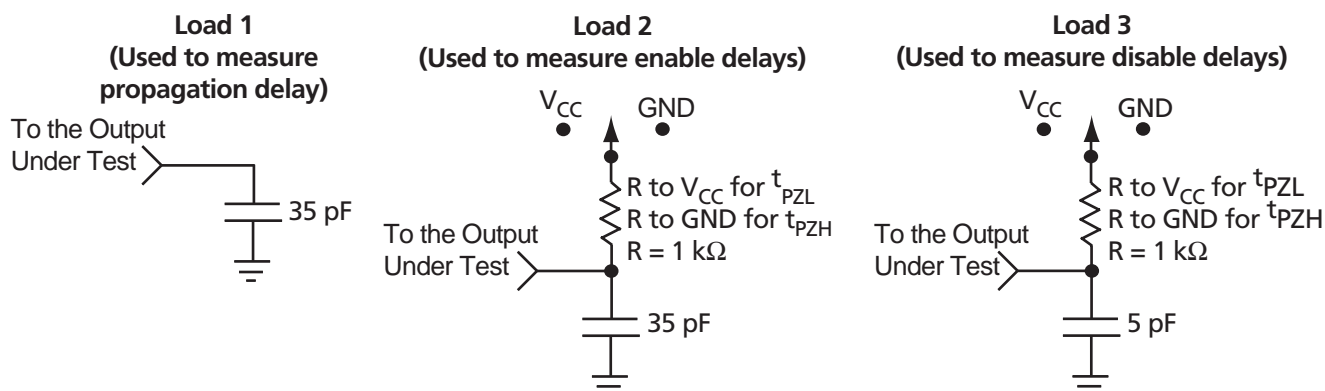


Figure 2-5 • AC Test Loads

Table 2-18 • A54SX08A Timing Characteristics

(Worst-Case Commercial Conditions $V_{CCA} = 2.25\text{ V}$, $V_{CCI} = 2.3\text{ V}$, $T_J = 70^\circ\text{C}$)

Parameter	Description	–2 Speed		–1 Speed		Std. Speed		–F Speed		Units
		Min.	Max.	Min.	Max.	Min.	Max.	Min.	Max.	
2.5 V LVCMOS Output Module Timing ^{1,2}										
t _{DLH}	Data-to-Pad Low to High		3.9		4.4		5.2		7.2	ns
t _{DHL}	Data-to-Pad High to Low		3.0		3.4		3.9		5.5	ns
t _{DHLS}	Data-to-Pad High to Low—low slew		13.3		15.1		17.7		24.8	ns
t _{ENZL}	Enable-to-Pad, Z to L		2.8		3.2		3.7		5.2	ns
t _{ENZLS}	Data-to-Pad, Z to L—low slew		13.7		15.5		18.2		25.5	ns
t _{ENZH}	Enable-to-Pad, Z to H		3.9		4.4		5.2		7.2	ns
t _{ENLZ}	Enable-to-Pad, L to Z		2.5		2.8		3.3		4.7	ns
t _{ENHZ}	Enable-to-Pad, H to Z		3.0		3.4		3.9		5.5	ns
d _{TLH} ³	Delta Low to High		0.037		0.043		0.051		0.071	ns/pF
d _{THL} ³	Delta High to Low		0.017		0.023		0.023		0.037	ns/pF
d _{THLS} ³	Delta High to Low—low slew		0.06		0.071		0.086		0.117	ns/pF

Note:

- Delays based on 35 pF loading.
- The equivalent I/O Attribute Editor settings for 2.5 V LVCMOS is 2.5 V LVTTTL in the software.
- To obtain the slew rate, substitute the appropriate Delta value, load capacitance, and the V_{CCI} value into the following equation:

$$\text{Slew Rate [V/ns]} = (0.1 * V_{CCI} - 0.9 * V_{CCI}) / (C_{load} * d_{T[HL|HL|HLS]})$$
where C_{load} is the load capacitance driven by the I/O in pF
 $d_{T[HL|HL|HLS]}$ is the worst case delta value from the datasheet in ns/pF.

Table 2-25 • A54SX16A Timing Characteristics

(Worst-Case Commercial Conditions $V_{CCA} = 2.25\text{ V}$, $V_{CCI} = 2.25\text{ V}$, $T_J = 70^\circ\text{C}$)

Parameter	Description	–3 Speed ¹		–2 Speed		–1 Speed		Std. Speed		–F Speed		Units
		Min.	Max.	Min.	Max.	Min.	Max.	Min.	Max.	Min.	Max.	
2.5 V LVCMOS Output Module Timing ^{2, 3}												
t _{DLH}	Data-to-Pad Low to High	3.4		3.9		4.5		5.2		7.3		ns
t _{DHL}	Data-to-Pad High to Low	2.6		3.0		3.3		3.9		5.5		ns
t _{DHLS}	Data-to-Pad High to Low—low slew	11.6		13.4		15.2		17.9		25.0		ns
t _{ENZL}	Enable-to-Pad, Z to L	2.4		2.8		3.2		3.7		5.2		ns
t _{ENZLS}	Data-to-Pad, Z to L—low slew	11.8		13.7		15.5		18.2		25.5		ns
t _{ENZH}	Enable-to-Pad, Z to H	3.4		3.9		4.5		5.2		7.3		ns
t _{ENLZ}	Enable-to-Pad, L to Z	2.1		2.5		2.8		3.3		4.7		ns
t _{ENHZ}	Enable-to-Pad, H to Z	2.6		3.0		3.3		3.9		5.5		ns
d _{TLH} ⁴	Delta Low to High	0.031		0.037		0.043		0.051		0.071		ns/pF
d _{THL} ⁴	Delta High to Low	0.017		0.017		0.023		0.023		0.037		ns/pF
d _{THLS} ⁴	Delta High to Low—low slew	0.057		0.06		0.071		0.086		0.117		ns/pF

Note:

1. All –3 speed grades have been discontinued.
2. Delays based on 35 pF loading.
3. The equivalent IO Attribute settings for 2.5 V LVCMOS is 2.5 V LVTTTL in the software.
4. To obtain the slew rate, substitute the appropriate Delta value, load capacitance, and the V_{CCI} value into the following equation:

$$\text{Slew Rate [V/ns]} = (0.1 * V_{CCI} - 0.9 * V_{CCI}) / (C_{load} * d_{T[LH|HL|HLS]})$$
where C_{load} is the load capacitance driven by the I/O in pF
 $d_{T[LH|HL|HLS]}$ is the worst case delta value from the datasheet in ns/pF.

Table 2-26 • **A54SX16A Timing Characteristics**
(Worst-Case Commercial Conditions $V_{CCA} = 2.25\text{ V}$, $V_{CCI} = 3.0\text{ V}$, $T_J = 70^\circ\text{C}$)

Parameter	Description	–3 Speed ¹		–2 Speed		–1 Speed		Std. Speed		–F Speed		Units
		Min.	Max.	Min.	Max.	Min.	Max.	Min.	Max.	Min.	Max.	
3.3 V PCI Output Module Timing ²												
t _{DLH}	Data-to-Pad Low to High	2.0		2.3		2.6		3.1		4.3		ns
t _{DHL}	Data-to-Pad High to Low	2.2		2.5		2.8		3.3		4.6		ns
t _{ENZL}	Enable-to-Pad, Z to L	1.4		1.7		1.9		2.2		3.1		ns
t _{ENZH}	Enable-to-Pad, Z to H	2.0		2.3		2.6		3.1		4.3		ns
t _{ENLZ}	Enable-to-Pad, L to Z	2.5		2.8		3.2		3.8		5.3		ns
t _{ENHZ}	Enable-to-Pad, H to Z	2.2		2.5		2.8		3.3		4.6		ns
d _{TLH} ³	Delta Low to High	0.025		0.03		0.03		0.04		0.045		ns/pF
d _{THL} ³	Delta High to Low	0.015		0.015		0.015		0.015		0.025		ns/pF
3.3 V LVTTTL Output Module Timing ⁴												
t _{DLH}	Data-to-Pad Low to High	2.8		3.2		3.6		4.3		6.0		ns
t _{DHL}	Data-to-Pad High to Low	2.7		3.1		3.5		4.1		5.7		ns
t _{DHLS}	Data-to-Pad High to Low—low slew	9.5		10.9		12.4		14.6		20.4		ns
t _{ENZL}	Enable-to-Pad, Z to L	2.2		2.6		2.9		3.4		4.8		ns
t _{ENZLS}	Enable-to-Pad, Z to L—low slew	15.8		18.9		21.3		25.4		34.9		ns
t _{ENZH}	Enable-to-Pad, Z to H	2.8		3.2		3.6		4.3		6.0		ns
t _{ENLZ}	Enable-to-Pad, L to Z	2.9		3.3		3.7		4.4		6.2		ns
t _{ENHZ}	Enable-to-Pad, H to Z	2.7		3.1		3.5		4.1		5.7		ns
d _{TLH} ³	Delta Low to High	0.025		0.03		0.03		0.04		0.045		ns/pF
d _{THL} ³	Delta High to Low	0.015		0.015		0.015		0.015		0.025		ns/pF
d _{THLS} ³	Delta High to Low—low slew	0.053		0.053		0.067		0.073		0.107		ns/pF

Notes:

1. All –3 speed grades have been discontinued.
2. Delays based on 10 pF loading and 25 Ω resistance.
3. To obtain the slew rate, substitute the appropriate Delta value, load capacitance, and the V_{CCI} value into the following equation:

$$\text{Slew Rate [V/ns]} = (0.1 * V_{CCI} - 0.9 * V_{CCI}) / (C_{load} * d_{T[HL|HL|HLS]})$$
 where C_{load} is the load capacitance driven by the I/O in pF
 $d_{T[HL|HL|HLS]}$ is the worst case delta value from the datasheet in ns/pF.
4. Delays based on 35 pF loading.

Table 2-28 • A54SX32A Timing Characteristics (Continued)
(Worst-Case Commercial Conditions, $V_{CCA} = 2.25\text{ V}$, $V_{CCI} = 3.0\text{ V}$, $T_J = 70^\circ\text{C}$)

Parameter	Description	-3 Speed ¹		-2 Speed		-1 Speed		Std. Speed		-F Speed		Units
		Min.	Max.	Min.	Max.	Min.	Max.	Min.	Max.	Min.	Max.	
t_{INYH}	Input Data Pad to Y High 5 V PCI		0.7		0.8		0.9		1.0		1.4	ns
t_{INYL}	Input Data Pad to Y Low 5 V PCI		0.9		1.1		1.2		1.4		1.9	ns
t_{INYH}	Input Data Pad to Y High 5 V TTL		0.9		1.1		1.2		1.4		1.9	ns
t_{INYL}	Input Data Pad to Y Low 5 V TTL		1.4		1.6		1.8		2.1		2.9	ns
Input Module Predicted Routing Delays³												
t_{IRD1}	FO = 1 Routing Delay		0.3		0.3		0.3		0.4		0.6	ns
t_{IRD2}	FO = 2 Routing Delay		0.4		0.5		0.5		0.6		0.8	ns
t_{IRD3}	FO = 3 Routing Delay		0.5		0.6		0.7		0.8		1.1	ns
t_{IRD4}	FO = 4 Routing Delay		0.7		0.8		0.9		1		1.4	ns
t_{IRD8}	FO = 8 Routing Delay		1.2		1.4		1.5		1.8		2.5	ns
t_{IRD12}	FO = 12 Routing Delay		1.7		2		2.2		2.6		3.6	ns

Notes:

1. All -3 speed grades have been discontinued.
2. For dual-module macros, use $t_{PD} + t_{RD1} + t_{PDn}$, $t_{RCO} + t_{RD1} + t_{PDn}$, or $t_{PD1} + t_{RD1} + t_{SUD}$, whichever is appropriate.
3. Routing delays are for typical designs across worst-case operating conditions. These parameters should be used for estimating device performance. Post-route timing analysis or simulation is required to determine actual performance.

Table 2-29 • **A54SX32A Timing Characteristics**
(Worst-Case Commercial Conditions $V_{CCA} = 2.25\text{ V}$, $V_{CCI} = 2.25\text{ V}$, $T_J = 70^\circ\text{C}$)

Parameter	Description	–3 Speed*		–2 Speed		–1 Speed		Std. Speed		–F Speed		Units
		Min.	Max.	Min.	Max.	Min.	Max.	Min.	Max.	Min.	Max.	
Dedicated (Hardwired) Array Clock Networks												
t _{HCKH}	Input Low to High (Pad to R-cell Input)		1.7		2.0		2.2		2.6		4.0	ns
t _{HCKL}	Input High to Low (Pad to R-cell Input)		1.7		2.0		2.2		2.6		4.0	ns
t _{HPWH}	Minimum Pulse Width High	1.4		1.6		1.8		2.1		2.9		ns
t _{HPWL}	Minimum Pulse Width Low	1.4		1.6		1.8		2.1		2.9		ns
t _{HCKSW}	Maximum Skew		0.6		0.6		0.7		0.8		1.3	ns
t _{HP}	Minimum Period	2.8		3.2		3.6		4.2		5.8		ns
f _{HMAX}	Maximum Frequency		357		313		278		238		172	MHz
Routed Array Clock Networks												
t _{RCKH}	Input Low to High (Light Load) (Pad to R-cell Input)		2.2		2.5		2.9		3.4		4.7	ns
t _{RCKL}	Input High to Low (Light Load) (Pad to R-cell Input)		2.1		2.4		2.7		3.2		4.4	ns
t _{RCKH}	Input Low to High (50% Load) (Pad to R-cell Input)		2.4		2.7		3.1		3.6		5.1	ns
t _{RCKL}	Input High to Low (50% Load) (Pad to R-cell Input)		2.2		2.5		2.8		3.3		4.6	ns
t _{RCKH}	Input Low to High (100% Load) (Pad to R-cell Input)		2.5		2.9		3.2		3.8		5.3	ns
t _{RCKL}	Input High to Low (100% Load) (Pad to R-cell Input)		2.4		2.7		3.1		3.6		5.0	ns
t _{RPWH}	Minimum Pulse Width High	1.4		1.6		1.8		2.1		2.9		ns
t _{RPWL}	Minimum Pulse Width Low	1.4		1.6		1.8		2.1		2.9		ns
t _{RCKSW}	Maximum Skew (Light Load)		1.0		1.1		1.3		1.5		2.1	ns
t _{RCKSW}	Maximum Skew (50% Load)		0.9		1.0		1.2		1.4		1.9	ns
t _{RCKSW}	Maximum Skew (100% Load)		0.9		1.0		1.2		1.4		1.9	ns

Note: *All –3 speed grades have been discontinued.

Table 2-33 • **A54SX32A Timing Characteristics**
(Worst-Case Commercial Conditions $V_{CCA} = 2.25\text{ V}$, $V_{CCI} = 3.0\text{ V}$, $T_J = 70^\circ\text{C}$)

Parameter	Description	–3 Speed ¹		–2 Speed		–1 Speed		Std. Speed		–F Speed		Units
		Min.	Max.	Min.	Max.	Min.	Max.	Min.	Max.	Min.	Max.	
3.3 V PCI Output Module Timing ²												
t _{DLH}	Data-to-Pad Low to High	1.9		2.2		2.4		2.9		4.0		ns
t _{DHL}	Data-to-Pad High to Low	2.0		2.3		2.6		3.1		4.3		ns
t _{ENZL}	Enable-to-Pad, Z to L	1.4		1.7		1.9		2.2		3.1		ns
t _{ENZH}	Enable-to-Pad, Z to H	1.9		2.2		2.4		2.9		4.0		ns
t _{ENLZ}	Enable-to-Pad, L to Z	2.5		2.8		3.2		3.8		5.3		ns
t _{ENHZ}	Enable-to-Pad, H to Z	2.0		2.3		2.6		3.1		4.3		ns
d _{TLH} ³	Delta Low to High	0.025		0.03		0.03		0.04		0.045		ns/pF
d _{THL} ³	Delta High to Low	0.015		0.015		0.015		0.015		0.025		ns/pF
3.3 V LVTTTL Output Module Timing ⁴												
t _{DLH}	Data-to-Pad Low to High	2.6		3.0		3.4		4.0		5.6		ns
t _{DHL}	Data-to-Pad High to Low	2.6		3.0		3.3		3.9		5.5		ns
t _{DHLS}	Data-to-Pad High to Low—low slew	9.0		10.4		11.8		13.8		19.3		ns
t _{ENZL}	Enable-to-Pad, Z to L	2.2		2.6		2.9		3.4		4.8		ns
t _{ENZLS}	Enable-to-Pad, Z to L—low slew	15.8		18.9		21.3		25.4		34.9		ns
t _{ENZH}	Enable-to-Pad, Z to H	2.6		3.0		3.4		4.0		5.6		ns
t _{ENLZ}	Enable-to-Pad, L to Z	2.9		3.3		3.7		4.4		6.2		ns
t _{ENHZ}	Enable-to-Pad, H to Z	2.6		3.0		3.3		3.9		5.5		ns
d _{TLH} ³	Delta Low to High	0.025		0.03		0.03		0.04		0.045		ns/pF
d _{THL} ³	Delta High to Low	0.015		0.015		0.015		0.015		0.025		ns/pF
d _{THLS} ³	Delta High to Low—low slew	0.053		0.053		0.067		0.073		0.107		ns/pF

Notes:

1. All –3 speed grades have been discontinued.
2. Delays based on 10 pF loading and 25 Ω resistance.
3. To obtain the slew rate, substitute the appropriate Delta value, load capacitance, and the V_{CCI} value into the following equation:

$$\text{Slew Rate [V/ns]} = (0.1 * V_{CCI} - 0.9 * V_{CCI}) / (C_{load} * d_{T[HL|HL|HLS]})$$
 where C_{load} is the load capacitance driven by the I/O in pF
 $d_{T[HL|HL|HLS]}$ is the worst case delta value from the datasheet in ns/pF.
4. Delays based on 35 pF loading.

Table 2-34 • A54SX32A Timing Characteristics
(Worst-Case Commercial Conditions $V_{CCA} = 2.25\text{ V}$, $V_{CCI} = 4.75\text{ V}$, $T_J = 70^\circ\text{C}$)

Parameter	Description	–3 Speed ¹		–2 Speed		–1 Speed		Std. Speed		–F Speed		Units
		Min.	Max.	Min.	Max.	Min.	Max.	Min.	Max.	Min.	Max.	
5 V PCI Output Module Timing ²												
t _{DLH}	Data-to-Pad Low to High	2.1		2.4		2.8		3.2		4.5		ns
t _{DHL}	Data-to-Pad High to Low	2.8		3.2		3.6		4.2		5.9		ns
t _{ENZL}	Enable-to-Pad, Z to L	1.3		1.5		1.7		2.0		2.8		ns
t _{ENZH}	Enable-to-Pad, Z to H	2.1		2.4		2.8		3.2		4.5		ns
t _{ENLZ}	Enable-to-Pad, L to Z	3.0		3.5		3.9		4.6		6.4		ns
t _{ENHZ}	Enable-to-Pad, H to Z	2.8		3.2		3.6		4.2		5.9		ns
d _{TLH} ³	Delta Low to High	0.016		0.016		0.02		0.022		0.032		ns/pF
d _{THL} ³	Delta High to Low	0.026		0.03		0.032		0.04		0.052		ns/pF
5 V TTL Output Module Timing ⁴												
t _{DLH}	Data-to-Pad Low to High	1.9		2.2		2.5		2.9		4.1		ns
t _{DHL}	Data-to-Pad High to Low	2.5		2.9		3.3		3.9		5.4		ns
t _{DHLS}	Data-to-Pad High to Low—low slew	6.6		7.6		8.6		10.1		14.2		ns
t _{ENZL}	Enable-to-Pad, Z to L	2.1		2.4		2.7		3.2		4.5		ns
t _{ENZLS}	Enable-to-Pad, Z to L—low slew	7.4		8.4		9.5		11.0		15.4		ns
t _{ENZH}	Enable-to-Pad, Z to H	1.9		2.2		2.5		2.9		4.1		ns
t _{ENLZ}	Enable-to-Pad, L to Z	3.6		4.2		4.7		5.6		7.8		ns
t _{ENHZ}	Enable-to-Pad, H to Z	2.5		2.9		3.3		3.9		5.4		ns
d _{TLH} ³	Delta Low to High	0.014		0.017		0.017		0.023		0.031		ns/pF
d _{THL} ³	Delta High to Low	0.023		0.029		0.031		0.037		0.051		ns/pF
d _{THLS} ³	Delta High to Low—low slew	0.043		0.046		0.057		0.066		0.089		ns/pF

Notes:

1. All –3 speed grades have been discontinued.
2. Delays based on 50 pF loading.
3. To obtain the slew rate, substitute the appropriate Delta value, load capacitance, and the V_{CCI} value into the following equation:

$$\text{Slew Rate [V/ns]} = (0.1 * V_{CCI} - 0.9 * V_{CCI}) / (C_{load} * d_{T[HL|HL|HLS]})$$
 where C_{load} is the load capacitance driven by the I/O in pF
 $d_{T[HL|HL|HLS]}$ is the worst case delta value from the datasheet in ns/pF.
4. Delays based on 35 pF loading.

Table 2-36 • A54SX72A Timing Characteristics (Continued)
(Worst-Case Commercial Conditions $V_{CCA} = 2.25\text{ V}$, $V_{CCI} = 2.25\text{ V}$, $T_J = 70^\circ\text{C}$)

Parameter	Description	–3 Speed*		–2 Speed		–1 Speed		Std. Speed		–F Speed		Units
		Min.	Max.	Min.	Max.	Min.	Max.	Min.	Max.	Min.	Max.	
t_{QCKH}	Input Low to High (100% Load) (Pad to R-cell Input)		3.0		3.4		3.9		4.6		6.4	ns
t_{QCHKL}	Input High to Low (100% Load) (Pad to R-cell Input)		2.9		3.4		3.8		4.5		6.3	ns
t_{QPWH}	Minimum Pulse Width High	1.5		1.7		2.0		2.3		3.2		ns
t_{QPWL}	Minimum Pulse Width Low	1.5		1.7		2.0		2.3		3.2		ns
t_{QCKSW}	Maximum Skew (Light Load)		0.2		0.3		0.3		0.3		0.5	ns
t_{QCKSW}	Maximum Skew (50% Load)		0.4		0.5		0.5		0.6		0.9	ns
t_{QCKSW}	Maximum Skew (100% Load)		0.4		0.5		0.5		0.6		0.9	ns

Note: *All –3 speed grades have been discontinued.

Package Pin Assignments

208-Pin PQFP

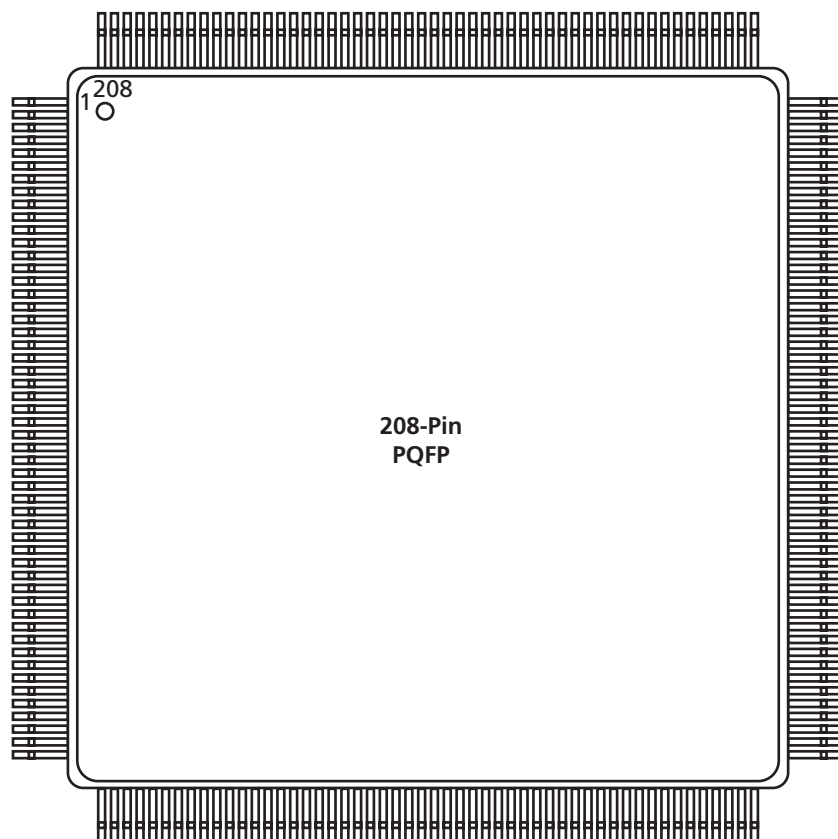


Figure 3-1 • 208-Pin PQFP (Top View)

Note

For Package Manufacturing and Environmental information, visit Resource center at <http://www.actel.com/products/rescenter/package/index.html>.

144-Pin TQFP			
Pin Number	A54SX08A Function	A54SX16A Function	A54SX32A Function
1	GND	GND	GND
2	TDI, I/O	TDI, I/O	TDI, I/O
3	I/O	I/O	I/O
4	I/O	I/O	I/O
5	I/O	I/O	I/O
6	I/O	I/O	I/O
7	I/O	I/O	I/O
8	I/O	I/O	I/O
9	TMS	TMS	TMS
10	V _{CCI}	V _{CCI}	V _{CCI}
11	GND	GND	GND
12	I/O	I/O	I/O
13	I/O	I/O	I/O
14	I/O	I/O	I/O
15	I/O	I/O	I/O
16	I/O	I/O	I/O
17	I/O	I/O	I/O
18	I/O	I/O	I/O
19	NC	NC	NC
20	V _{CCA}	V _{CCA}	V _{CCA}
21	I/O	I/O	I/O
22	TRST, I/O	TRST, I/O	TRST, I/O
23	I/O	I/O	I/O
24	I/O	I/O	I/O
25	I/O	I/O	I/O
26	I/O	I/O	I/O
27	I/O	I/O	I/O
28	GND	GND	GND
29	V _{CCI}	V _{CCI}	V _{CCI}
30	V _{CCA}	V _{CCA}	V _{CCA}
31	I/O	I/O	I/O
32	I/O	I/O	I/O
33	I/O	I/O	I/O
34	I/O	I/O	I/O
35	I/O	I/O	I/O
36	GND	GND	GND
37	I/O	I/O	I/O

144-Pin TQFP			
Pin Number	A54SX08A Function	A54SX16A Function	A54SX32A Function
38	I/O	I/O	I/O
39	I/O	I/O	I/O
40	I/O	I/O	I/O
41	I/O	I/O	I/O
42	I/O	I/O	I/O
43	I/O	I/O	I/O
44	V _{CCI}	V _{CCI}	V _{CCI}
45	I/O	I/O	I/O
46	I/O	I/O	I/O
47	I/O	I/O	I/O
48	I/O	I/O	I/O
49	I/O	I/O	I/O
50	I/O	I/O	I/O
51	I/O	I/O	I/O
52	I/O	I/O	I/O
53	I/O	I/O	I/O
54	PRB, I/O	PRB, I/O	PRB, I/O
55	I/O	I/O	I/O
56	V _{CCA}	V _{CCA}	V _{CCA}
57	GND	GND	GND
58	NC	NC	NC
59	I/O	I/O	I/O
60	HCLK	HCLK	HCLK
61	I/O	I/O	I/O
62	I/O	I/O	I/O
63	I/O	I/O	I/O
64	I/O	I/O	I/O
65	I/O	I/O	I/O
66	I/O	I/O	I/O
67	I/O	I/O	I/O
68	V _{CCI}	V _{CCI}	V _{CCI}
69	I/O	I/O	I/O
70	I/O	I/O	I/O
71	TDO, I/O	TDO, I/O	TDO, I/O
72	I/O	I/O	I/O
73	GND	GND	GND
74	I/O	I/O	I/O

176-Pin TQFP

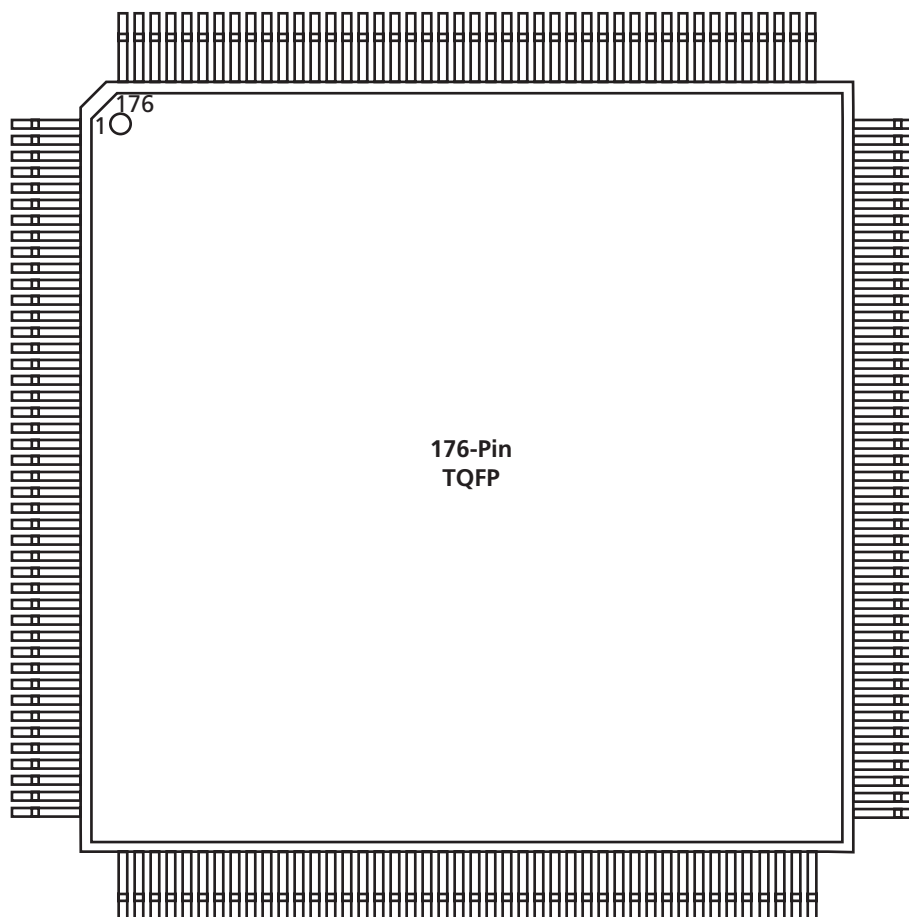


Figure 3-4 • 176-Pin TQFP (Top View)

Note

For Package Manufacturing and Environmental information, visit Resource center at <http://www.actel.com/products/rescenter/package/index.html>.

256-Pin FBGA			
Pin Number	A54SX16A Function	A54SX32A Function	A54SX72A Function
A1	GND	GND	GND
A2	TCK, I/O	TCK, I/O	TCK, I/O
A3	I/O	I/O	I/O
A4	I/O	I/O	I/O
A5	I/O	I/O	I/O
A6	I/O	I/O	I/O
A7	I/O	I/O	I/O
A8	I/O	I/O	I/O
A9	CLKB	CLKB	CLKB
A10	I/O	I/O	I/O
A11	I/O	I/O	I/O
A12	NC	I/O	I/O
A13	I/O	I/O	I/O
A14	I/O	I/O	I/O
A15	GND	GND	GND
A16	GND	GND	GND
B1	I/O	I/O	I/O
B2	GND	GND	GND
B3	I/O	I/O	I/O
B4	I/O	I/O	I/O
B5	I/O	I/O	I/O
B6	NC	I/O	I/O
B7	I/O	I/O	I/O
B8	V _{CCA}	V _{CCA}	V _{CCA}
B9	I/O	I/O	I/O
B10	I/O	I/O	I/O
B11	NC	I/O	I/O
B12	I/O	I/O	I/O
B13	I/O	I/O	I/O
B14	I/O	I/O	I/O
B15	GND	GND	GND
B16	I/O	I/O	I/O
C1	I/O	I/O	I/O
C2	TDI, I/O	TDI, I/O	TDI, I/O
C3	GND	GND	GND
C4	I/O	I/O	I/O
C5	NC	I/O	I/O

256-Pin FBGA			
Pin Number	A54SX16A Function	A54SX32A Function	A54SX72A Function
C6	I/O	I/O	I/O
C7	I/O	I/O	I/O
C8	I/O	I/O	I/O
C9	CLKA	CLKA	CLKA
C10	I/O	I/O	I/O
C11	I/O	I/O	I/O
C12	I/O	I/O	I/O
C13	I/O	I/O	I/O
C14	I/O	I/O	I/O
C15	I/O	I/O	I/O
C16	I/O	I/O	I/O
D1	I/O	I/O	I/O
D2	I/O	I/O	I/O
D3	I/O	I/O	I/O
D4	I/O	I/O	I/O
D5	I/O	I/O	I/O
D6	I/O	I/O	I/O
D7	I/O	I/O	I/O
D8	PRA, I/O	PRA, I/O	PRA, I/O
D9	I/O	I/O	QCLKD
D10	I/O	I/O	I/O
D11	NC	I/O	I/O
D12	I/O	I/O	I/O
D13	I/O	I/O	I/O
D14	I/O	I/O	I/O
D15	I/O	I/O	I/O
D16	I/O	I/O	I/O
E1	I/O	I/O	I/O
E2	I/O	I/O	I/O
E3	I/O	I/O	I/O
E4	I/O	I/O	I/O
E5	I/O	I/O	I/O
E6	I/O	I/O	I/O
E7	I/O	I/O	QCLKC
E8	I/O	I/O	I/O
E9	I/O	I/O	I/O
E10	I/O	I/O	I/O